



Title of Change:	Release of NLHV4157NDFT2G Rev B with ONC18EE_USR Wafer Technology from ON Gresham and Assembly in ON Leshan using SC88 Packaging	
Proposed first ship date:	15 June 2018 or earlier upon customer approval	
Contact information:	Contact your local ON Semiconductor Sales Office or <Riva.Ni@onsemi.com>	
Samples:	Contact your local ON Semiconductor Sales Office	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <ChangKit.Mok@onsemi.com>	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.	
Change Part Identification:	Affected products will be identified by date code. The rest of the product marking will remain the same.	
Change category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____	
Change Sub-Category(s):	<div style="display: flex; flex-wrap: wrap;"> <div style="width: 33%;"> <input type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Manufacturing Process Change </div> <div style="width: 33%;"> <input type="checkbox"/> Material Change <input checked="" type="checkbox"/> Product specific change </div> <div style="width: 33%;"> <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____ </div> </div>	
Sites Affected:	ON Semiconductor Sites: ON Gresham, Oregon	External Foundry/Subcon Sites: None
Description and Purpose:		
<p>This PCN is to notify customers that ON has qualified an improved version of NLHV4157NDFT2G to increase yield by eliminating random high leakage observed at higher range of supply voltage (VEE=-8V to -12V). This was accomplished by changing the SEL input to a higher breakdown voltage (>16.5V).</p>		

**Reliability Data Summary:****DEVICE NAME:** NLHV4157NDFT2G**REFERENCE:** S38133, S39098, L44638**PACKAGE:** SC-88

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, V _{EE} = -12V	1008 hours	0/240
LTOL	JESD22-A108	Ta=-40°C, V _{EE} = -12V	1008 hours	0/240
HTSL	JESD22-A103	Ta=150°C	1008 hours	0/240
PC	J-STD-020 JESD-A113	MSL1@260°C	-	0/240
TC + PC	JESD22-A104	Ta=-65°C to +150°C	1000 cycles	0/240

Electrical Characteristic Summary:

Electrical characteristics are not impacted (no change in data sheet)

List of Affected Standard Parts:

Part Number	Qualification Vehicle
NLHV4157NDFT2G	NLHV4157NDFT2G